

## Opening and Introductory

It is our great pleasure that we can have the chance to meet each other and discuss the "Current Status and Problems on Surface Analysis by Electron Spectroscopy". On behalf of the Institute for Transfer of Industrial Technology (ITIT), the Agency of Industrial Science and Technology (AIST) /MITI, I express the heartiest appreciation to all of you for joining this symposium. Today more than 30 speakers/commentators are invited from 10 countries including Japan.

As all of you know well, the surface analysis by electron spectroscopy has the history of about 30 years. Tremendous amount of efforts have been devoted to the development of the techniques during these years, and in some cases the development of the techniques such as AES and XPS has been intimately connected with the development of new industries. Nowadays, AES and XPS are widely applied as powerful techniques for surface and interface analysis in various fields of industries.

The reliability of the techniques have been improved largely during these 10 years, for which the VAMAS-SCA (Surface Chemical Analysis) activities contributed largely as all of you will agree. Now the techniques are coming to be accepted as the tools for not only surface qualitative analysis but also for the surface quantitative analysis, although the improvement of the reliability has yet to be pursued continuously. I believe, therefore, that it is a good chance to survey the present ability and to focus attention to the present problems of the surface analytical techniques through stimulating discussions among researchers from Asian and European countries as well as USA.

Today, following the keynote lecture by Dr. C.J. Powell, the first chairperson of the VAMAS-SCA technical working area, recent research works in the three major subjects are presented by speakers and commentators including several national representatives of VAMAS-SCA. I hope active discussion today will bring forth valuable knowledge for all of you to obtain a full scope for "Future Direction in Surface Analysis by AES/XPS", which is scheduled to be discussed at the satellite symposium tomorrow.

The Secretariat of the ITIT Symposium  
S. Ichimura / ETL